

# CBCS SCHEME

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18EC72

Seventh Semester B.E. Degree Examination, Dec.2024/Jan.2025

## VLSI Design

Time: 3 hrs.

Max. Marks: 100

*Note: Answer any FIVE full questions, choosing ONE full question from each module.*

### Module-1

- 1 a. With relevant diagrams, explain the operation of nmos enhancement mode transistor for 3 different regions of operation. (08 Marks)
- b. Explain the operation of mux based positive edge triggered D-flip flop with neat circuit and waveform. (08 Marks)
- c. Explain the operation of tri-state inverter. (04 Marks)

**OR**

- 2 a. Explain the following non-ideal I-V effects :
  - i) Velocity saturation and mobility degradation (08 Marks)
  - ii) Channel length modulation (08 Marks)
- b. Discuss the DC characteristics of CMOS inverter with necessary tabulation. (08 Marks)
- c. Write a short note on noise margin. (04 Marks)

### Module-2

- 3 a. Draw and explain the cross sections while manufacturing n-well. (08 Marks)
- b. Define the following with respect to MOS fabrication process:
  - i) Photo lithography
  - ii) Oxidation
  - iii) Chemical vapor deposition
  - iv) Self aligned process. (06 Marks)
- c. Draw the circuit and standard cell layout of 3 - i/p NAND gate (06 Marks)

**OR**

- 4 a. What is scaling? Why scaling is needed? Assume that scaling factor  $s = 1.24$  and current process technology is 180 nm. What is the gate length of the new technology? (04 Marks)
- b. Explain constant field scaling? What is the effect of constant field scaling on  $C_{ox}$ ,  $I_D$ , power dissipation and power density. (08 Marks)
- c. Explain the following limitations imposed by small-device geometries:
  - i) DIBL
  - ii) Drain punch through (08 Marks)

Important Note : 1. On completing your answers, compulsorily draw diagonal cross lines on the remaining blank pages.  
2. Any revealing of identification, appeal to evaluator and /or equations written eg, 42+8 = 50, will be treated as malpractice.

Module-3

- 5 a. Define the following timing parameters:  
 i) Propagation delay time      ii) Contamination delay time  
 iii) Rise time                      iv) Fall time (04 Marks)
- b. Explain Elmore delay. Compute the Elmore delay for  $V_{out}$  in the below given second order RC system. [Refer Fig.Q5(b)]

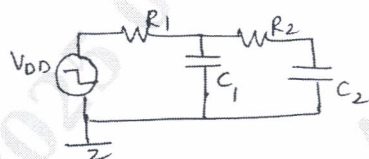


Fig.Q5(b)

(06 Marks)

- c. What is logical effort? Discuss and calculate the logical effort for inverter, 3- i/p NAND gate and 3 i/p NOR gate. (10 Marks)

**OR**

- 6 a. Explain cascode voltage switch logic circuits with an example of 2 i/p AND/NAND logic gate. Mention any 2 advantages and limitations. (08 Marks)
- b. What is ratioed circuits? Explain pseudo nMOS and ganged CMOS logic circuits. (08 Marks)
- c. Write a short note on complementary pass transistor logic (CPL). (04 Marks)

Module-4

- 7 a. Discuss various conventional CMOS latches. (10 Marks)
- b. Explain pulsed latch with relevant waveform. (06 Marks)
- c. What is synchronous resettable latch? (04 Marks)

**OR**

- 8 a. Explain the operation of dynamic D-latch and discuss charge leakage when clock goes to zero. (08 Marks)
- b. Explain the operation of ratioless logic enhancement - load dynamic shift register. (05 Marks)
- c. Explain the working of dynamic CMOS logic circuit with an example. Also discuss its limitations. (07 Marks)

Module-5

- 9 a. Explain the operation of 3-Transistor DRAM cell with read/write circuitry and typical waveforms. (10 Marks)
- b. Explain the Read and Write operation in 6T-SRAM cell with read and write timing diagram. (10 Marks)

**OR**

- 10 Write a short note on :
- Testers and test fixtures
  - Observability and controllability
  - Adhoc testing
  - Built-In Self Test (BIST)

(20 Marks)